## **EAST Search History**

| Ref<br># | Hits  | Search Query  | DBs   | Default<br>Operator | Plurals | Time Stamp       |
|----------|-------|---|---|---------------------|---------|------------------|
| L1       | 13493 | ((209/571) or (209/573) or (324/158.<br>1) or (324/759) or (324/764) or<br>(324/765) or (700/96) or (700/108) or<br>(700/109) or (700/121)).CCLS.   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | OFF     | 2007/04/13 11:21 |
| L2       | 219   | ((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse)))   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2007/04/13 11:21 |
| L4       | 5     | ("4953277"   "5256578"   "5550838"  <br>"5895962"   "5907492").PN.  | US-PGPUB;<br>USPAT;<br>USOCR                            | OR                  | ON      | 2007/04/13 11:24 |
| L5       | 20    | ("4958373"   "4967381"   "5103166"  <br>"5105362"   "5217834"   "5219765"  <br>"5226118"   "5271796"   "5289113"  <br>"5294812"   "5301143"   "5420796"  <br>"5440493"   "5442561"   "5450326"  <br>"5467304"   "5483175"   "5495417"  <br>"5511005"   "5568408").PN. | US-PGPUB;<br>USPAT;<br>USOCR                            | · OR                | ON      | 2007/04/13 11:24 |